

In the claims:

Please amend the claims as follows:

1. (Currently Amended): An apparatus for indicating real time focus in a scanning microscope, the apparatus comprising:

a detector for ~~detecting~~ converting a radiation beam generated by the scanning microscope into an analog electrical signal from the scanning microscope;
one or more bandpass filters for filtering the ~~detected~~ analog electrical signal, wherein the one or more bandpass filters are tuned to a desired range of frequencies; and
one or more power indicators for detecting and displaying average power of the filtered analog electrical signal of a corresponding bandpass filter.

2. (Original): The apparatus of Claim 1, wherein the one or more bandpass filters comprises at least one of a low, medium, or high pass filter.

3. (Original): The apparatus of Claim 1, further comprising a focusing device for generating a focusing signal based on the detected average power and focusing the scanning microscope based on the generated focusing signal.

4. (Original): The apparatus of Claim 3, wherein the focusing device automatically performs generating and focusing.

5. (Original): The apparatus of Claim 1, wherein the scanning microscope is a confocal microscope.

6. (Currently Amended): A method for indicating real time focus in a scanning microscope, the method comprising:

detecting ~~converting a radiation beam generated by the scanning microscope into an analog electrical signal from the scanning microscope~~;
filtering the ~~detected~~ analog electrical signal according to one or more frequency ranges; and
detecting average power of the filtered electrical signal for each of the one or more frequency ranges; and
displaying each of the detected average powers of the analog electrical signal.

7. (Original): The method of Claim 6, wherein filtering is performed by one or more bandpass filters.

8. (Original): The method of Claim 7, wherein the one or more bandpass filters comprises at least one of a low, medium, or high pass filter.

9. (Original): The method of Claim 6, further comprising:
generating a focusing signal based on the detected average power; and
focusing the scanning microscope based on the generated focusing signal.

10. (Original): The method of Claim 9, wherein focusing comprises automatically focusing.

11. (Original): The method of Claim 6, wherein the scanning microscope is a confocal microscope.

12. (Currently Amended): An apparatus for indicating real time focus in a scanning microscope, the apparatus comprising:

~~detecting~~ converting a radiation beam generated by the scanning microscope into an analog electrical signal ~~from the scanning microscope~~;
one or more bandpass filters for filtering the ~~detected~~ analog electrical signal, wherein the one or more bandpass filters are tuned to a desired range of frequencies; and
a focusing device for generating a focusing signal based on the filtered analog electrical signal and focusing the scanning microscope based on the generated focusing signal.

13. (Original): The apparatus of Claim 12, wherein the focusing device automatically performs generating and focusing.

14. (Currently Amended): A method for indicating real time focus in a scanning microscope, a method comprising:

~~detecting~~ converting a radiation beam generated by the scanning microscope into an analog electrical signal ~~from the scanning microscope~~;
filtering the ~~detected~~ analog electrical signal according to a desired range of frequencies;
generating a focusing signal based on the filtered analog electrical signal; and
focusing the scanning microscope based on the generated focusing signal.


15. (Original): The method of Claim 14, wherein generating and focusing are automatically performed.

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